

**Preliminary**

TOSHIBA Insulated Gate Bipolar Transistor Silicon N Channel IGBT

# GT15J121

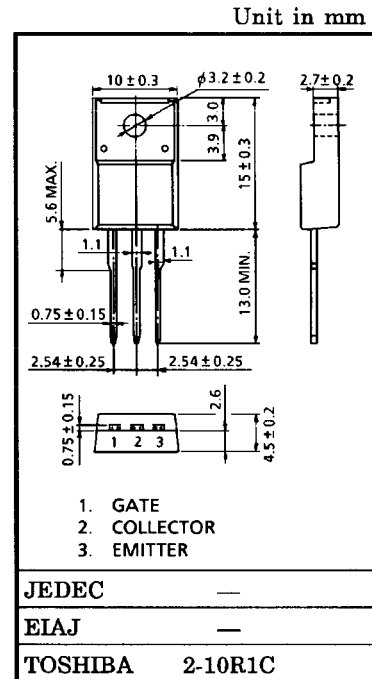
High Power Switching Applications

Fast Switching Applications

- The 4th generation
- Enhancement-mode
- Ultra Fast Switching(UFS :Operating frequency up to 150kHz(Reference)
  - High speed : $t_r=0.03 \mu s$ (typ.)  
: $t_f=0.08 \mu s$ (typ.)
  - Low switching loss : $E_{on}=0.23mJ$ (typ.)  
: $E_{off}=0.18mJ$ (typ.)

### Maximum Ratings (Ta=25°C)

Characteristic	Symbol	Ratings	Unit
Collector-emitter voltage	$V_{CES}$	600	V
Gate-emitter voltage	$V_{GES}$	$\pm 20$	V
Collector current	DC	$I_C$	15
	1ms	$I_{CP}$	45
Collector power dissipation (Tc=25°C)	$P_C$	35	W
Junction temperature	$T_j$	150	°C
Storage temperature range	$T_{stg}$	-55~150	°C



Weight : 1.7g

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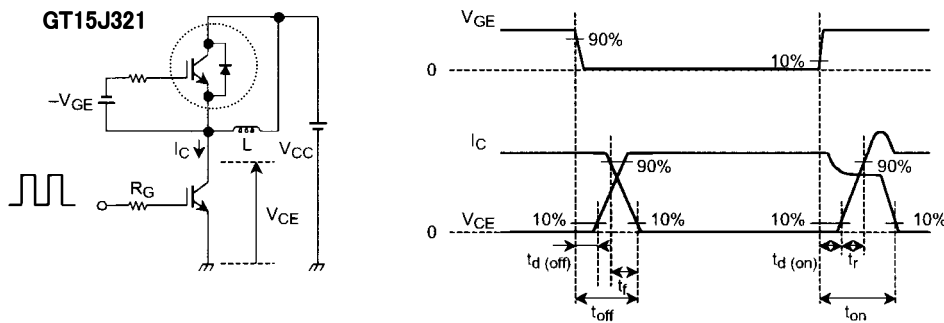
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### Electrical Characteristics(Ta=25°C)

Characteristic		Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current		$I_{GES}$	$V_{GE} = \pm 20V, V_{CE} = 0$	-	-	$\pm 500$	nA
Collector cut-off current		$I_{CES}$	$V_{CE} = 600V, V_{GE} = 0$	-	-	1.0	mA
Gate-emitter cut-off voltage		$V_{GE(OFF)}$	$I_C = 1.5mA, V_{CE} = 5V$	3.0	-	6.0	V
Collector-emitter saturation voltage		$V_{CE(sat)}$	$I_C = 15A, V_{GE} = 15V$	-	2.7	3.5	V
Input capacitance		$C_{ies}$	$V_{CE} = 10V, V_{GE} = 0, f = 1MHz$	-	1300	-	pF
Switching time	Turn-on delay time	$t_{d(on)}$	Inductive Load $V_{CC} = 300V, I_C = 15A$ $V_{GG} = +15V, R_G = 27\Omega$  (Note 1) (Note 2)	-	0.04	-	$\mu s$
	Rise Time	$t_r$		-	0.03	-	
	Turn-on Time	$t_{on}$		-	0.12	-	
	Turn-off delay time	$t_{d(off)}$		-	0.10	-	
	Fall Time	$t_f$		-	0.08	0.15	
	Turn-off Time	$t_{off}$		-	0.20	-	
Switching loss	Turn-on switching loss	$E_{on}$	-	0.23	-	mJ	
	Turn-off switching loss	$E_{off}$	-	0.18	-		
Thermal resistance		$R_{th(j-c)}$	—	-	-	3.57	°C/W

Note1: Switching time measurement circuit and input/output waveforms



Note 2: Switching loss measurement waveforms

